

XSD50-01WL-ICF-SYS

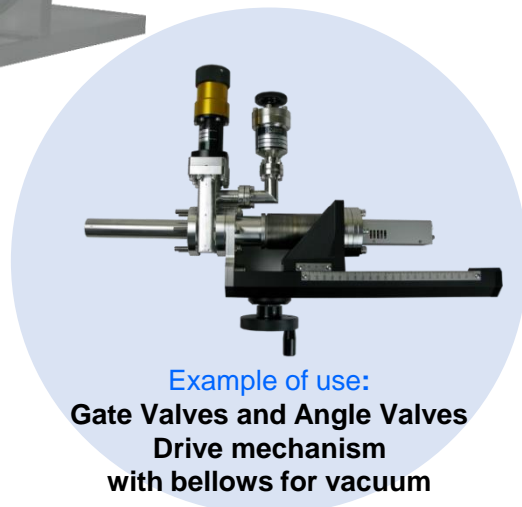
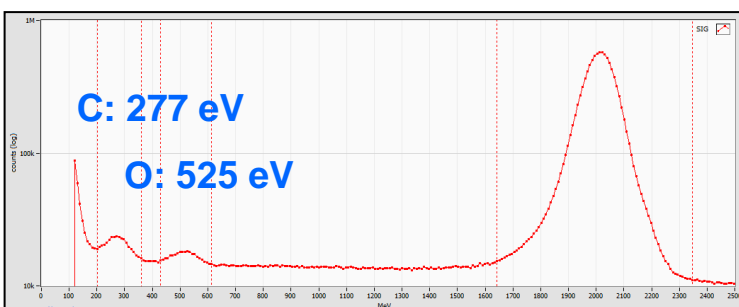
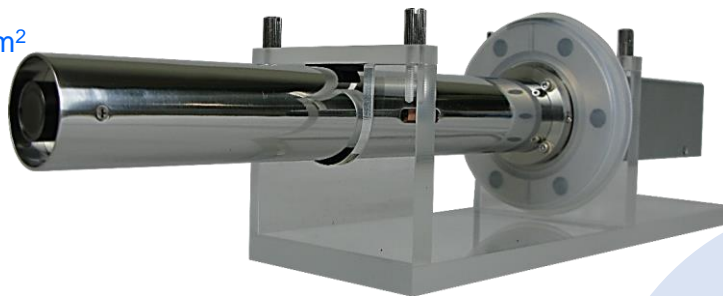
Transistor reset and DSP processing have been properly performed to significantly improve throughput.

It is possible to measure light elements such as carbon in the soft x-ray region.

Windless type 1-element silicon drift detector

10⁻⁷ Pa
Corresponding Vacuum

XSD50-01WL-ICF
65mm² collimated 50mm²



Digital Spectrometer

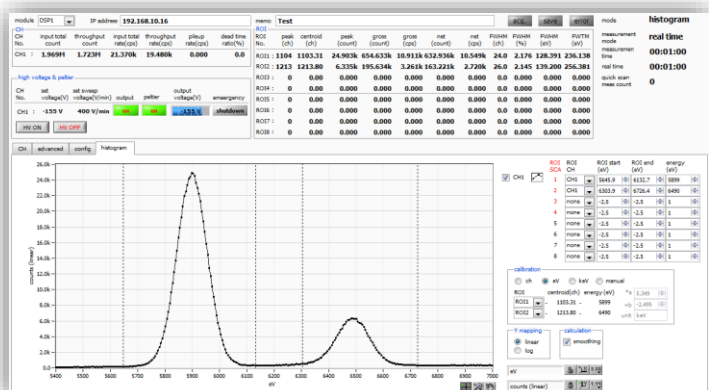
APU101X

Built-in power supply for detector (high voltage, for preamplifier, for peltier cooling)



Specifications

Functions	Histogram, List, Quick-Scan, ROI-SCA
Energy resolution (typ.)	125eV@5.9keV 2us 150eV@5.9keV 0.15us
Throughput	Max. 150kcps @ 2us Max. 1000kcps @ 0.15us
SDD power supply	-200 V, ±5V, +3.3V
Communication I/F	Ethernet, TCP/IP
Dimensions (mm)	210 (W) x 45 (H) x 275 (D)
Accessories	Application for data acquisition, Sample program, Instruction Manual



Application window for data collection

*Images is for illustration purpose.

*Please note that contents may change without prior notice.

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